

Si5386 Data Sheet

12-Channel, Any-Frequency, Any-Output wireless Jitter Attenuator / Clock Multiplier with Ultra-Low Noise

The Si5386 is an ultra high performance wireless jitter attenuator with any frequency outputs for eCPRI (ethernet-based Common Public Radio Interface) applications, which demand the highest level of integration and phase noise performance. Based on Silicon Laboratories' 4th generation DSPLL technology, the Si5386 combines frequency synthesis and jitter attenuation in a highly integrated digital solution with a cost-effective oscillator, and without the need of any external loop filter components. The fixed frequency oscillator provides frequency stability for free-run and holdover modes. This all-digital solution provides superior performance that is highly immune to external board disturbances such as power supply noise.

eCPRI-based remote radio heads and fixed wireless systems require a diverse set of clocks such as ADC/DAC, RF LOs, and Ethernet clocks. The Si5386 architecture is designed to deliver high-performance JESD204B DCLK and SYSREF clock pairs and flexible any-rate clocks for non-CPRI clocks such as Ethernet and system reference clocks all from a single IC.

Applications:

- Wireless Infrastructure
 - eCPRI RRH (Remote Radio Head)
 - BBU (Baseband Unit)
 - · Small Cell and µBTS
- · DOCSIS
- · Test and Measurement

IN SEL OUTOA OUTO INT IN3/FB_IN ÷INT \sum OUT1 INT INT \sum OUT2 OUT3 INT ┤⋩ -_ OUT4 INT OUT5 INT - \ 12C SEL +INT ->= OUT6 DA/SDIO A1/SDO SCLK SPI/ I²C ->= INT OUT7 A0/CS OUT INT 125 NVM INT -_ OUT9 LOL INTP \searrow OUT9A int

SYNC OF

PDN RS1

KEY FEATURES

- Flexible timing in a single IC
 - Generates any combination of output frequencies from any input frequency
- Input frequency range:
 - Differential: 7.68 MHz to 750 MHz
 - LVCMOS: 7.68 MHz to 250 MHz
- Output frequency range (Integer):
 - Differential: up to 3 GHz
- Output frequency range (fractional):
 Differential: up to 735 MHz
 - LVCMOS: up to 250 MHz
- Ultra-low RMS jitter:
 - 72 fs typ (12 kHz–20 MHz)
- Phase noise of 122.88MHz carrier frequency:
- 118 dBc/Hz @ 100Hz offset
- ITU-T G.8262 compliant

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1. Features List

The Si5386 features are listed below:

- ITU-T G.8262 compliant
- Flexible timing in a single IC
 - Generates any combination of output frequencies from any input frequency
- Input frequency range:
 - Differential: 7.68 MHz to 750 MHz
 - LVCMOS: 7.68 MHz to 250 MHz
- Output frequency range (Integer):
 - Differential: up to 2.94912 GHz with JESD204B support
- Output frequency range (fractional):
 - Differential: up to 735 MHz
 - LVCMOS: up to 250 MHz
- Ultra-low RMS jitter (12kHz 20MHz):
 - 72 fs typ at 122.88 MHz
 - 88 fs typ at 156.25 MHz
 - 79 fs typ at 322.265625 MHz
- Programmable jitter attenuation bandwidth from 1 Hz to 4 kHz
- Phase noise of 122.88 MHz carrier frequency:
 - -118 dBc/Hz @ 100 Hz offset
 - -133 dBc/Hz @ 1 kHz offset
 - -142 dBc/Hz @ 10 kHz offset
 - -149 dBc/Hz @ 100 kHz offset
 - · -154 dBc/Hz @ 1 MHz offset
- Highly configurable outputs compatible with LVDS, LVPECL, LVCMOS, CML, and HCSL. CML outputs can be programmed to have 100-1600 mVpp single-ended swing.

- Status monitoring (LOS, OOF, LOL)
- · Pin controlled input switching
- DSPLL with special wireless calibration
- Optional zero delay mode
- · Hitless input clock switching: automatic or manual
- · Automatic free-run and holdover modes
- Fastlock feature
- · Glitchless on the fly output frequency changes
- Core voltage:
 - VDD: 1.8 V ±5%
 - VDDA: 3.3 V ±5%
- Independent output clock supply pins: 3.3 V, 2.5 V, or 1.8 V
- Output-output skew: 20 ps typ
- Serial interface: I2C or SPI
- · In-circuit programmable with non-volatile OTP memory
- ClockBuilder ProTM software simplifies device configuration
- Temperature range: –40 to +85 °C
- · Pb-free, RoHS-6 compliant

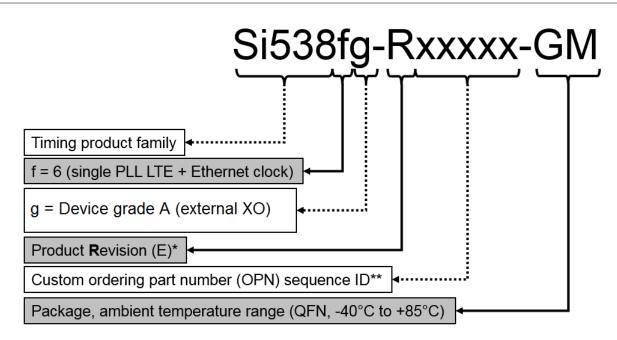
2. Ordering Guide

Ordering Part Num- ber (OPN)	Reference	Number of In- put/Output Clocks	Output Clock Fre- quency Range (MHz)	Supported Fre- quency Synthesis Modes	Package	Tempera- ture Range
Si5386						
Si5386A-E-GM ^{1, 2}	External XO	4/12	0.0001 to 2949.12 MHz	Integer and Fractional	64-QFN 9×9 mm	–40 to 85 °C

Notes:

1. Add an R at the end of the OPN to denote tape and reel ordering options.

2. Custom, factory preprogrammed devices are available. Ordering part numbers are assigned by Silicon Labs and the ClockBuilder Pro software utility. Custom part number format is "Si5386A-Exxxxx-GM" where "xxxxx" is a unique numerical sequence representing the preprogrammed configuration.



*See Ordering Guide table for current product revision.

** (Optional) 5 digits; assigned by ClockBuilder Pro for Custom, factory-preprogrammed OPN devices only; (The "xxxxx" field is not included for "Base" OPNs).

Figure 2.1. Ordering Part Number Fields

3. Functional Description

The Si5386's internal DSPLL provides jitter attenuation and any-frequency multiplication of the selected input frequency without the need for (external) VCXOs and loop filters. Input switching is controlled manually or automatically using an internal state machine. The external oscillator provides a frequency reference which determines output frequency stability and accuracy while the device is in freerun or holdover mode. The high-performance MultiSynthdividers (N) generate integer or fractionally related output frequencies for the output stage. A crosspoint switch connects any of the MultiSynth generated frequencies to any of the outputs. Additional integer division (R) determines the final output frequency. Further, the DSPLL is specially calibrated for ultra-low phase noise when configured for CPRI frequencies with JESD204B outputs. This integration provides a clock-tree-on-a-chip solution for applications that need a mix of 4G/ CPRI, Ethernet, and general-purpose frequencies.

3.1 Frequency Configuration

The frequency configuration of the DSPLL is programmable through the serial interface and can also be stored in non-volatile memory. The combination of fractional input dividers (P_n/P_d) , fractional frequency multiplication (M_n/M_d) , fractional output MultiSynth division (N_n/N_d) , and integer output division (R_n) allows the generation of virtually any output frequency on any of the outputs with very low-phase noise suitable for wireless applications when synthesizing CPRI frequencies. All divider values for a specific frequency plan are easily determined using the ClockBuilder Pro utility.

3.2 DSPLL Loop Bandwidth

The DSPLL loop bandwidth determines the amount of input clock jitter attenuation. Register configurable DSPLL loop bandwidth settings in the range of 1 Hz to 4 kHz are available for selection. Since the loop bandwidth is controlled digitally, the DSPLL will always remain stable with less than 0.1 dB of peaking regardless of the loop bandwidth selection.

3.3 Fastlock Feature

Selecting a low DSPLL loop bandwidth (e.g., 1 Hz) will generally lengthen the lock acquisition time. The fastlock feature allows setting a temporary Fastlock Loop Bandwidth that is used during the lock acquisition process. Higher fastlock loop bandwidth settings will enable the DSPLLs to lock faster. Fastlock Loop Bandwidth settings of in the range of 100 Hz to 4 kHz are available for selection. The DSPLL will revert to its normal loop bandwidth once lock acquisition has completed.

3.4 Modes of Operation

Once initialization is complete the DSPLL operates in one of four modes: Free-run Mode, Lock Acquisition Mode, Locked Mode, or Holdover Mode. A state diagram showing the modes of operation is shown in Figure 3.1 Modes of Operation on page 7. The following sections describe each of these modes in greater detail.

3.4.1 Initialization and Reset

Once power is applied, the device begins an initialization period where it downloads default register values and configuration data from NVM and performs other initialization tasks. Communicating with the device through the serial interface is possible once this initialization period is complete. No clocks are generated until the initialization is complete. There are two types of resets available. A hard reset is functionally similar to a device power-up. All registers are restored to the values stored in NVM, and all circuits including the serial interface is restored to their initial state. A hard reset is initiated using the RSTb pin or by asserting the hard reset register bit. A soft reset bypasses the NVM download. It is simply used to initiate register configuration changes.

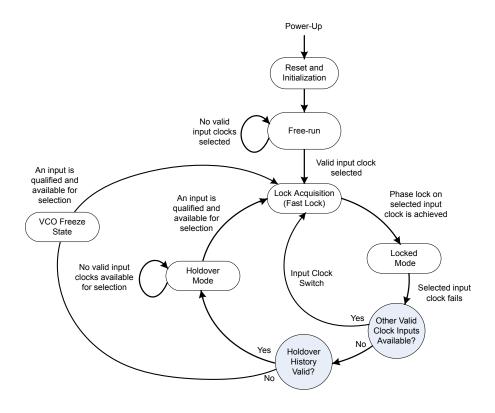


Figure 3.1. Modes of Operation

3.4.2 Freerun Mode

The DSPLL will automatically enter freerun mode once power is applied to the device and initialization is complete. The frequency accuracy of the generated output clocks in freerun mode is entirely dependent on the frequency accuracy of the reference clock on the XA/XB pins. For example, if the oscillator stability is ±50 ppm, then all the output clocks will be generated at their configured frequency with ±50 ppm stability in freerun mode. Any drift of the oscillator frequency is tracked at the output clock frequencies. Free run mode is maintained as long as no input clocks are valid.

3.4.3 Lock Acquisition Mode

The device monitors all inputs for a valid clock. If at least one valid clock is available for synchronization, the DSPLL automatically starts the lock acquisition process. If the fast lock feature is enabled, the DSPLL acquires lock using the Fastlock Loop Bandwidth setting and then transition to the DSPLL Loop Bandwidth setting when lock acquisition is complete. During lock acquisition, the output generates a clock that follows the VCO frequency change as it pulls in to the input clock frequency.

3.4.4 Locked Mode

Once locked, the DSPLL generates output clocks that are both frequency and phase locked to their selected input clocks. At this point, any oscillator frequency drift does not affect the output frequency. A loss of lock pin (LOL) and status bit indicate when lock is achieved. See 3.7.4 LOL Detection for more details on the operation of the loss-of-lock circuit.

3.4.5 Holdover Mode

If holdover history is valid, the DSPLL automatically enters holdover mode when the selected input clock becomes invalid and no other valid input clocks are available for selection. The DSPLL uses an averaged input clock frequency as its final holdover frequency to minimize the disturbance of the output clock phase and frequency when an input clock suddenly fails. The holdover circuit for the DSPLL stores up to 120 seconds of historical frequency data while locked to a valid clock input. The final averaged holdover frequency value is calculated from a programmable window within the stored historical frequency data. Both the window size and the delay are programmable as shown in the figure below. The window size determines the amount of holdover frequency averaging. The delay value allows ignoring frequency data that may be corrupt just before the input clock failure.

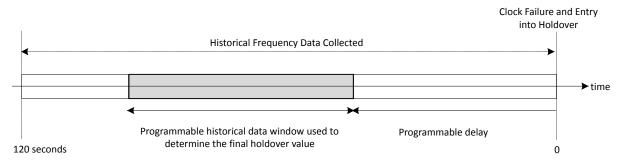


Figure 3.2. Programmable Holdover Window

When entering holdover, the DSPLL pulls its output clock frequency to the calculated averaged holdover frequency. While in holdover, the output frequency drift is entirely dependent on the external reference clock connected to the XA/XB pins. If the clock input becomes valid, the DSPLL automatically exits the holdover mode and re-acquires lock to the new input clock. This process involves pulling the output clock frequency to achieve frequency and phase lock with the input clock. This pull-in process is glitchless and its rate is controlled by the DSPLL or the Fastlock bandwidth.

The DSPLL output frequency when exiting holdover can be ramped (recommended). Just before the exit is initiated, the difference between the current holdover frequency and the new desired frequency is measured. Using the calculated difference and a user-selectable ramp rate, the output is linearly ramped to the new frequency. The ramp rate can be 0.2 ppm/s, 40,000 ppm/s, or any of about 40 values in between. The DSPLL loop BW does not limit or affect ramp rate selections (and vice versa). CBPro defaults to ramped exit from holdover. The same ramp rate settings are used for both exit from holdover and ramped input switching. For more information on ramped input switching, see 3.6.4 Ramped Input Switching.

Note: If ramped holdover exit is not selected, the holdover exit is governed either by (1) the DSPLL loop BW or (2) a user-selectable holdover exit BW.

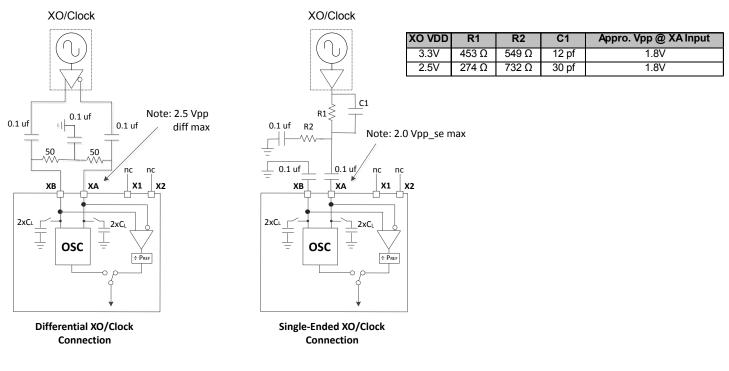
3.4.6 VCO Freeze Mode

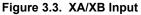
If holdover history is not valid, the DSPLL automatically enters VCO Freeze mode when the selected input clock becomes invalid and no other valid input clocks are available for selection. The DSPLL uses the last measured input frequency to set the output frequencies in the VCO Freeze mode. If an input clock becomes valid, the DSPLL automatically exits the VCO Freeze mode and re-acquires lock to the new input clock using either ramping or not just as if the DSPLL was exiting from Holdover Mode.

3.5 External Reference (XA/XB)

An external crystal oscillator (XO) is required to set the reference for the Si5386. Only a 54 MHz XO is used as the reference to the wireless jitter attenuator. For the jitter and phase noise performance that is specified in this data sheet, only the recommended 54 MHz XO's in the Si534x/8x Jitter Attenuators Recommended Crystal, TCXO and OCXOs Reference Manual can be used.

Place the XO as close to the XaXb pins as possible. See figure below for guidelines on how to connect the XO to the XaXb input. C1 increases the slew rate to the Xa input, which is needed to get the jitter and phase noise performance that is specifed in this data sheet.





3.6 Inputs (IN0, IN1, IN2, IN3)

There are four inputs that can be used to synchronize the DSPLL. The inputs accept both differential and single-ended clocks. Input selection can be manual (pin or register controlled) or automatic with user definable priorities.

3.6.1 Manual Input Switching (IN0, IN1, IN2, IN3)

Input clock selection can be made manually using the IN_SEL[1:0] pins or through a register. A register bit determines input selection as pin selectable or register selectable. The IN_SEL pins are selected by default. If there is no clock signal on the selected input, the device automatically enters free-run or holdover mode. When the zero delay mode is enabled, IN3 becomes the feedback input (FB_IN) and is not available for selection as a clock input.

IN_SE	:L[1:0]	Selected Input			
		Zero Delay Mode Disabled	Zero Delay Mode Enabled		
0	0	INO	INO		
0	1	IN1	IN1		
1	0	IN2	IN2		
1	1	IN3	Reserved		

Table 3.1. Manual Input Selection Using IN_SEL[1:0] Pins

3.6.2 Automatic Input Selection (IN0, IN1, IN2, IN3)

An automatic input selection state machine is available in addition to the manual switching option. In automatic mode, the selection criteria is based on input clock qualification, input priority, and the revertive option. Only input clocks that are valid can be selected by the automatic clock selection state machine. If there are no valid input clocks available the DSPLL will enter the holdover mode. With revertive switching enabled, the highest priority input with a valid input clock is always selected. If an input with a higher priority becomes valid then an automatic switchover to that input is initiated. With non-revertive switching, the active input always remains selected while it is valid. If it becomes invalid an automatic switchover to a valid input with the highest priority is initiated.

3.6.3 Hitless Input Switching

Hitless switching is a feature that prevents a phase offset from propagating to the output when switching between two clock inputs that have a fixed phase relationship. A hitless switch can only occur when the two input frequencies are frequency locked meaning that they have to be exactly at the same frequency, or at a fractional frequency relationship to each other. When hitless switching is enabled, the DSPLL simply absorbs the phase difference between the two input clocks during a input switch. When disabled, the phase difference between the two input clocks during a mean switch. The hitless switching feature supports clock frequencies down to the minimum input frequency of 7.68 MHz.

3.6.4 Ramped Input Switching

When switching between two plesiochronous input clocks (i.e., the frequencies are "almost the same" but not quite), ramped input switching should be enabled to ensure a smooth transition between the two inputs. Ramped input switching avoids frequency transients and overshoot when switching between frequencies and so is the default switching mode in CBPro. The feature should be turned off when switching between input clocks that are always frequency locked (i.e., are always the same exact frequency). The same ramp rate settings are used for both holdover exit and clock switching. For more information on ramped exit from holdover see 3.4.5 Holdover Mode.

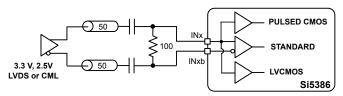
3.6.5 Glitchless Input Switching

The DSPLL has the ability of switching between two input clock frequencies that are up to 40 ppm apart. The DSPLL will pull-in to the new frequency using the DSPLL Loop Bandwidth or using the Fastlock Loop Bandwidth if enabled. The loss of lock (LOL) indicator will assert while the DSPLL is pulling-in to the new clock frequency. There will be no abrupt phase change at the output during the transition.

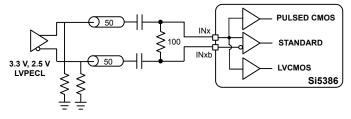
3.6.6 Input Configuration and Terminations

Each of the inputs can be configured as differential or single-ended LVCMOS. The recommended input termination schemes are in the figure below. Standard 50% duty cycle signals must be ac-coupled, while low duty cycle pulsed CMOS signals can be dc-coupled. Unused inputs can be disabled and left unconnected when not in use.

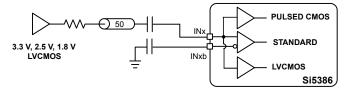
Standard AC-coupled Differential LVDS



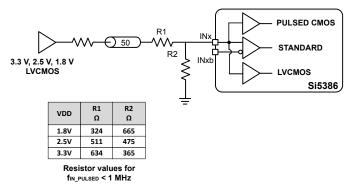
Standard AC-coupled Differential LVPECL



Standard AC-coupled Single-ended



Pulsed CMOS DC-coupled Single-ended





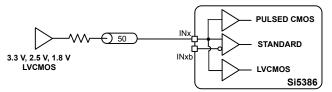


Figure 3.4. Termination of Differential and LVCMOS Input Signals

3.7 Fault Monitoring

All four input clocks (IN0, IN1, IN2, IN3/FB_IN) are monitored for loss of signal (LOS) and out-of-frequency (OOF) as shown in the figure below. The reference at the XA/XB pins is also monitored for LOS since it provides a critical reference clock for the DSPLL. There is also a Loss Of Lock (LOL) indicator which is asserted when the DSPLL loses synchronization.

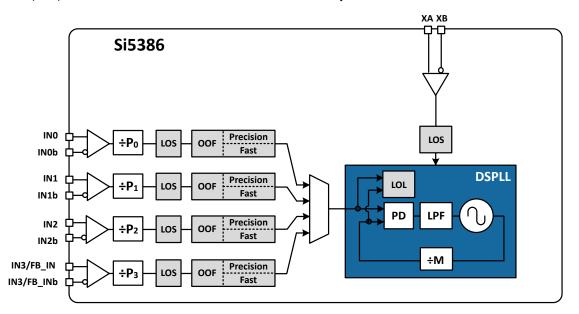


Figure 3.5. Si5386 Fault Monitors (Grade A)

3.7.1 Input LOS Detection

The loss of signal monitor measures the period of each input clock cycle to detect phase irregularities or missing clock edges. Each of the input LOS circuits has its own programmable sensitivity which allows ignoring missing edges or intermittent errors. Loss of signal sensitivity is configurable using the ClockBuilder Pro utility.

The LOS status for each of the monitors is accessible by reading a status register. The live LOS register always displays the current LOS state and a sticky register always stays asserted until cleared. An option to disable any of the LOS monitors is also available.

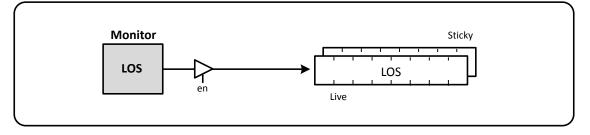


Figure 3.6. LOS Status Indicators

3.7.2 Reference Clock LOS Detection

A LOS monitor is available to ensure that the external reference oscillator is valid. By default the output clocks are disabled when XAXB_LOS is detected. This feature can be disabled such that the device will continue to produce output clocks when XAXB_LOS is detected.

3.7.3 OOF Detection

Each input clock is monitored for frequency accuracy with respect to a OOF reference which it considers as its "0_ppm" reference. This OOF reference can be selected as either:

- The XA/XB reference
- Any input clock (IN0, IN1, IN2, IN3)

The final OOF status is determined by the combination of both a precise OOF monitor and a fast OOF monitor as shown in the figure below. An option to disable either monitor is also available. The live OOF register always displays the current OOF state, and its sticky register bit stays asserted until cleared.

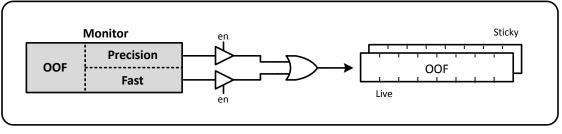


Figure 3.7. OOF Status Indicator

3.7.3.1 Precision OOF Monitor

The precision OOF monitor circuit measures the frequency of all input clocks to within ± 1 ppm accuracy with respect to the selected OOF frequency reference. A valid input clock frequency is one that remains within the OOF frequency range which is register configurable up to ± 20 ppm in steps of 1/16 ppm. A configurable amount of hysteresis is also available to prevent the OOF status from toggling at the failure boundary. An example is shown in the figure below. In this case, the OOF monitor is configured with a valid frequency range of ± 6 ppm and with 2 ppm of hysteresis. An option to use one of the input pins (IN0–IN3) as the 0 ppm OOF reference instead of the external XO reference is available. This option is register configurable.

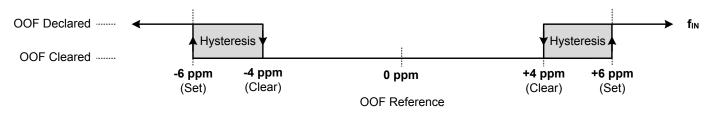


Figure 3.8. Example of Precise OOF Monitor Assertion and Deassertion Triggers

3.7.3.2 Fast OOF Monitor

Because the precision OOF monitor needs to provide 1/16 ppm of frequency measurement accuracy, it must measure the monitored input clock frequencies over a relatively long period of time. This may be too slow to detect an input clock that is quickly ramping in frequency. An additional level of OOF monitoring called the Fast OOF monitor runs in parallel with the precision OOF monitors to quickly detect a ramping input frequency. The Fast OOF monitor asserts OOF on an input clock frequency that has changed by greater than ±4000 ppm.

3.7.4 LOL Detection

The Loss Of Lock (LOL) monitor asserts a LOL register bit when the DSPLL has lost synchronization with its selected input clock.

There is also a dedicated loss of lock pin that reflects the loss of lock condition. The LOL monitor functions by measuring the frequency difference between the input and feedback clocks at the phase detector. There are two LOL frequency monitors, one that sets the LOL indicator (LOL Set) and another that clears the indicator (LOL Clear). An optional timer is available to delay clearing of the LOL indicator to allow additional time for the DSPLL to completely lock to the input clock. The timer is also useful to prevent the LOL indicator from toggling or chattering as the DSPLL completes lock acquisition. A block diagram of the LOL monitor is shown in the figure below. The live LOL register always displays the current LOL state and a sticky register always stays asserted until cleared. The LOL pin reflects the current state of the LOL monitor.

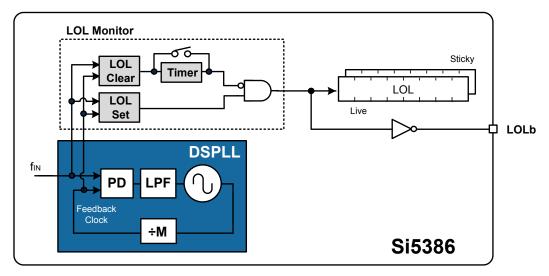


Figure 3.9. LOL Status Indicators

The LOL frequency monitors have an adjustable sensitivity which is register configurable from 0.1 ppm to 10,000 ppm. Having two separate frequency monitors allows for hysteresis to help prevent chattering of LOL status.

An example configuration where LOCK is indicated when there is less than 0.1 ppm frequency difference at the inputs of the phase detector and LOL is indicated when there's more than 1 ppm frequency difference is shown in the following figure.

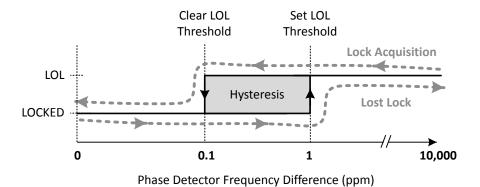


Figure 3.10. LOL Set and Clear Thresholds

Note: In this document, the terms, LVDS and LVPECL, refer to driver formats that are compatible with these signaling standards.

An optional timer is available to delay clearing of the LOL indicator to allow additional time for the DSPLL to completely lock to the input clock. The timer is also useful to prevent the LOL indicator from toggling or chattering as the DSPLL completes lock acquisition. The configurable delay value depends on frequency configuration and loop bandwidth of the DSPLL and is automatically calculated using the ClockBuilder Pro utility.

3.7.5 Interrupt Pin (INTRb)

An interrupt pin (INTRb) indicates a change in state of the status indicators (LOS, OOF, LOL, HOLD). Any of the status indicators are maskable to prevent assertion of the interrupt pin. The state of the INTRb pin is reset by clearing the status register that caused the interrupt.

3.8 Outputs

Each driver has a configurable voltage swing and common mode voltage covering a wide variety of differential signal formats. In addition to supporting differential signals, any of the outputs can be configured as single-ended LVCMOS (3.3 V, 2.5 V, or 1.8 V) providing up to 24 single-ended outputs, or any combination of differential and single-ended outputs.

3.8.1 Output Crosspoint

A crosspoint allows any of the output drivers to connect with any of the MultiSynths as shown in the figure below. The crosspoint configuration is programmable and can be stored in NVM so that the desired output configuration is ready at power up.

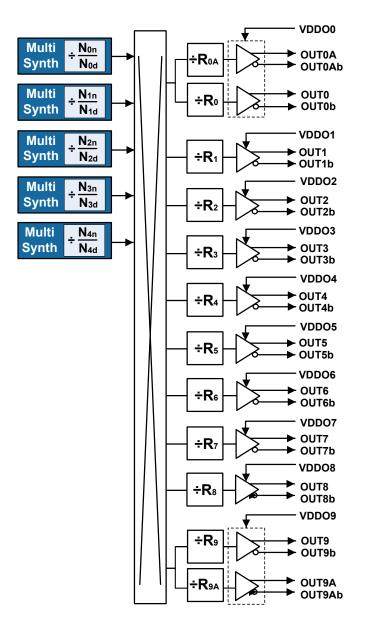


Figure 3.11. MultiSynth to Output Driver Crosspoint

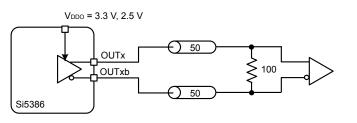
3.8.2 Output Signal Format

The differential output swing and common mode voltage are both fully programmable covering a wide variety of signal formats including LVDS and LVPECL. In addition to supporting differential signals, any of the outputs can be configured as LVCMOS (3.3 V, 2.5 V, or 1.8 V) drivers providing up to 24 single-ended outputs, or any combination of differential and single-ended outputs.

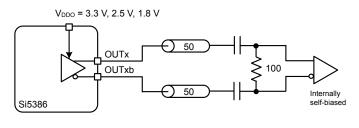
3.8.3 Output Terminations

The output drivers support both ac-coupled and dc-coupled terminations as shown in the following figure.

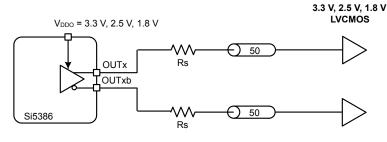
DC-coupled LVDS



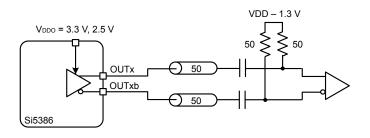
AC-coupled LVDS/LVPECL



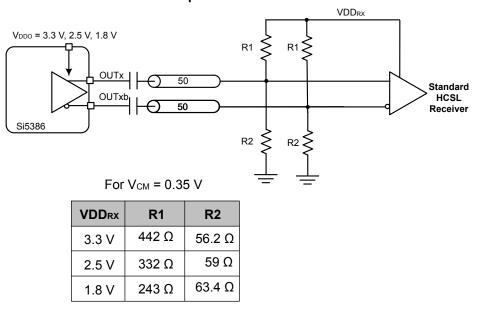
DC-coupled LVCMOS

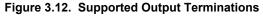


AC-coupled LVPECL / CML



AC-coupled HCSL





3.8.4 Programmable Common Mode Voltage For Differential Outputs

The common mode voltage (V_{CM}) for the differential modes are programmable so that LVDS specifications can be met and for the best signal integrity with different supply voltages. When dc coupling the output driver, it is essential that the receiver have a relatively high common mode impedance so that the common mode current from the output driver is very small.

3.8.5 LVCMOS Output Impedance and Drive Strength Selection

Each LVCMOS driver has a configurable output impedance to accommodate different trace impedances and drive strengths. A source termination resistor is recommended to help match the selected output impedance to the trace impedance. There are three programmable output impedance selections for each VDDO options as shown in the table below.

VDDO	OUTx_CMOS_DRV	Source Impedance (Zs)	Drive Strength (Iol/Ioh)
3.3 V	0x01	38 Ω	10 mA
	0x02	30 Ω	12 mA
	0x03*	22 Ω	17 mA
2.5 V	0x01	43 Ω	6 mA
	0x02	35 Ω	8 mA
	0x03*	24 Ω	11 mA
1.8 V	0x03*	31 Ω	5 mA
Note: Use of t	he lowest impedance setting is reco	mmended for all supply voltages for	best edge rates.

Table 3.2. LVCMOS Output Impedance and Drive Strength Selections

Note: Use of the lowest impedance setting is recommended for all supply voltages for best edge rates.

3.8.6 LVCMOS Output Signal Swing

The signal swing (V_{OI}/V_{OH}) of the LVCMOS output drivers is set by the voltage on the VDDO pins. Each output driver has its own VDDO pin allowing a unique output voltage swing for each of the LVCMOS drivers.

3.8.7 LVCMOS Output Polarity

When a driver is configured as an LVCMOS output, it generates a clock signal on both pins (OUTx and OUTxb). By default, the clock on the OUTx pin is generated with the same polarity (in phase) as the clock on the OUTxb pin. The polarity of these clocks is configurable, enabling complementary clock generation and/or inverted polarity with respect to other output drivers.

3.8.8 Output Enable/Disable

The OEb pin provides a convenient method of disabling or enabling all of the output drivers at the same time. When the OEb pin is held high all outputs will be disabled. When held low, the outputs will all be enabled. Outputs in the enabled state can still be individually disabled through register control.

3.8.9 Output Disable During LOL

By default, a DSPLL that is out of lock will generate either free-running clocks or generate clocks in holdover mode. There is an option to disable the outputs when a DSPLL is LOL. This option can be useful to force a downstream PLL into holdover.

3.8.10 Output Disable During Reference LOS

The external XA/XB reference provides a critical function for the operation of the DSPLLs. In the event of the XO failure, the device will assert an XAXB LOS alarm. By default, all outputs will be disabled during assertion of the XAXB LOS alarm. There is an option to leave the outputs enabled during an XAXB LOS alarm, but the frequency accuracy and stability is indeterminate during this fault condition.

3.8.11 Output Driver State When Disabled

The disabled state of an output driver is configurable as disable low or disable high.

3.8.12 Synchronous Output Disable Feature

The output drivers provide a selectable synchronous disable feature. Output drivers with this feature turned on will wait until a clock period has completed before the driver is disabled. This prevents unwanted runt pulses from occurring when disabling an output. When this feature is turned off, the output clock will disable immediately without waiting for the period to complete.

3.8.13 Zero Delay Mode

A zero delay mode is available for applications that require fixed and consistent minimum delay between the selected input and outputs. The zero delay mode is configured by opening the internal feedback loop through software configuration and closing the loop externally as shown in the figure below.

This helps to cancel out the internal delay introduced by the dividers, the crosspoint, the input, and the output drivers. Any one of the outputs can be fed back to the FB_IN pins, although using the output driver that achieves the shortest trace length will help to minimize the input-to-output delay. Note that the nominal input-to-output delay is the trace delay from OUTx to FB_IN. The OUT9A and FB_IN pins are recommended for the external feedback connection. The FB_IN input pins must be terminated and ac-coupled when zero delay mode is used. A differential external feedback path connection is necessary for best performance. Note that the hitless switching feature is not available when zero delay mode is enabled.

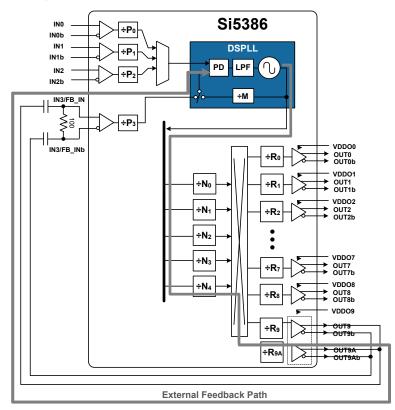


Figure 3.13. Si5386 Zero Delay Mode Setup

3.8.14 Output Divider (R) Synchronization

All the output R dividers are reset to a known state during the power-up initialization period. This ensures consistent and repeatable phase alignment across all output drivers. Resetting the device using the RSTb pin or asserting the hard reset bit will have the same result. R divider setting of 2 produces a 180 degree phase change compared to high R divider settings.

3.9 Power Management

Unused inputs and output drivers can be powered down when unused. Consult the Reference Manual and ClockBuilder Pro configuration utility for details.

3.10 In-Circuit Programming

The Si5386 is fully configurable using the serial interface (I²C or SPI). At power-up the device downloads its default register values from internal non-volatile memory (NVM). Application specific default configurations can be written into NVM allowing the device to generate specific clock frequencies at power-up. Writing default values to NVM is in-circuit programmable with normal operating power supply voltages applied to its V_{DD} and V_{DDA} pins. The NVM is two time writable. Once a new configuration has been written to NVM, the old configuration is no longer accessible. Refer to the Reference Manual for a detailed procedure for writing registers to NVM.

3.11 Serial Interface

Configuration and operation of the Si5386 is controlled by reading and writing registers using the I²C or SPI interface. The I2C_SEL pin selects I²C or SPI operation. Communication with both 3.3 V and 1.8 V host is supported. The SPI mode operates in either 4-wire or 3-wire. See the Reference Manual for details.

3.12 Custom Factory Preprogrammed Parts

For applications where a serial interface is not available for programming the device, custom pre-programmed parts can be ordered with a specific configuration written into NVM. A factory preprogrammed part will generate clocks at power-up. Custom, factory-preprogrammed devices are available. The ClockBuilder Pro custom part number wizard can be used to quickly and easily generate a custom part number for your configuration.

In less than three minutes, you will be able to generate a custom part number with a detailed data sheet addendum matching your design's configuration. Once you receive the confirmation email with the data sheet addendum, simply place an order with your local Silicon Labs sales representative. Samples of your preprogrammed device will typically ship in about two weeks.

3.13 Enabling Features and/or Configuration Settings Unavailable in ClockBuilder Pro for Factory Preprogrammed Devices

As with essentially all modern software utilities, ClockBuilder Pro is continually being updated and enhanced. By registering at www.silabs.com, you will be notified about changes and their impact. This update process will ultimately enable ClockBuilder Pro users to access all features and register setting values documented in this data sheet and the Reference Manual.

However, if you must enable or access a feature or register setting value so that the device starts up with this feature or a register setting, but the feature or register setting is not yet available in CBPro, you must contact a Silicon Labs applications engineer for assistance. One example of this type of feature or custom setting is the customizable output amplitude and common voltages for the clock outputs. After careful review of your project file and requirements, the Silicon Labs applications engineer will email back your CBPro project file with your specific features and register settings enabled using what's referred to as the manual "settings override" feature of CBPro. "Override" settings to match your request(s) will be listed in your design report file. Examples of setting "overrides" in a CBPro design report are shown in the following table.

Table 3.3. Setting Overrides

Location	Name	Туре	Target	Dec Value	Hex Value
0x0535[0]	FORCE_HOLD	No NVM	N/A	1	0x1
0x0B48[0:4]	OOF_DIV_CLK_DIS	User	OPN&EVB	0	0x00

Once you receive the updated design file, simply open it in CBPro. The device will begin operation after startup with the values in the NVM file. The flowchart for this process is shown in the following figure.

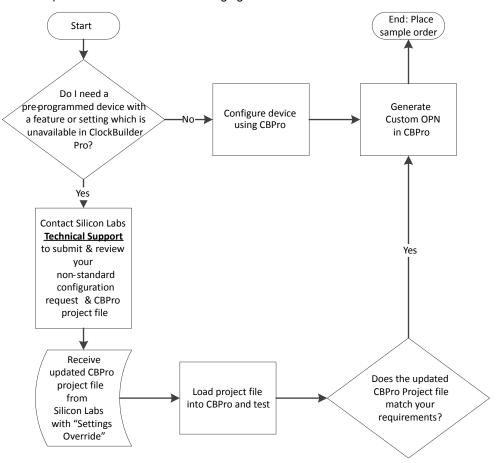


Figure 3.14. Process for Requesting Non-Standard CBPro Features

Note: Contact Silicon Labs Technical Support at www.silabs.com/support/Pages/default.aspx.

4. Register Map

The register map is divided into multiple pages where each page has 256 addressable registers. Page 0 contains frequently accessible registers, such as alarm status, resets, device identification, etc. Other pages contain registers that need less frequent access such as frequency configuration, and general device settings. A high level map of the registers is shown in "6.2. High-Level Register Map". Refer to the Reference Manual for a complete list of register descriptions and settings. Silicon Labs strongly recommends using Clock-Builder Pro to create and manage register settings.

4.1 Addressing Scheme

The device registers are accessible using a 16-bit address that consists of an 8-bit page address plus an 8-bit register address. By default, the page address is set to 0x00. Changing to another page is accomplished by writing to the "Set Page Address" byte located at address 0x01 of each page.

4.2 High-Level Register Map

16-Bit	Address	Content
8-bit Page Address	8-bit Register Address Range	Content
	00	Revision IDs
	01	Set Page Address
	02–0A	Device IDs
	0B–15	Alarm Status
	17–1B	INTR Masks
00	1C	Reset controls
	1D	FINC, FDEC Control Bits
	2B	SPI (3-Wire vs 4-Wire)
	2CE1	Alarm Configuration
	E2–E4	NVM Controls
	FE	Device Ready Status
	01	Set Page Address
01	08–3A	Output Driver Controls
01	41–42	Output Driver Disable Masks
	FE	Device Ready Status
	01	Set Page Address
	02–05	Reference Clock Frequency Adjust
	08–2F	Input Divider (P) Settings
02	30	Input Divider (P) Update Bits
	47–6A	Output Divider (R) Settings
	6B–72	User Scratch Pad Memory
	FE	Device Ready Status

Table 4.1. High-Level Register Map

16-Bi	t Address	Constant
8-bit Page Address	8-bit Register Address Range	Content
	01	Set Page Address
	02–37	MultiSynth Divider (N0–N4) Settings
	0C	MultiSynth Divider (N0) Update Bit
03	17	MultiSynth Divider (N1) Update Bit
	22	MultiSynth Divider (N2) Update Bit
	2D	MultiSynth Divider (N3) Update Bit
	38	MultiSynth Divider (N4) Update Bit
	39–58	FINC/FDEC Settings N0–N4
	59–62	Output Delay (Δt) Settings
	FE	Device Ready Status
04	87	Zero Delay Mode Set Up
	0E–14	Fast Lock Loop Bandwidth
	15–1F	Feedback Divider (M) Settings
	2A	Input Select Control
05	2B	Fast Lock Control
05	2C-35	Holdover Settings
	36	Input Clock Switching Mode Select
	38–39	Input Priority Settings
	3F	Holdover History Valid Data
06–08	00–FF	Reserved
09	01	Set Page Address
	1C	Zero Delay Mode Settings
	43	Control I/O Voltage Select
	49	Input Settings
10–FF	00–FF	Reserved

5. Electrical Specifications

Parameter	Symbol	Min	Тур	Max	Unit
Ambient Temperature	T _A	-40	25	85	°C
Maximum Junction Temperature	TJ _{MAX}	_	_	125	°C
Core Supply Voltage	V _{DD}	1.71	1.80	1.89	V
	V _{DDA}	3.14	3.30	3.47	V
Output Driver Supply Voltage	V _{DDO}	3.14	3.30	3.47	V
		2.38	2.50	2.62	V
		1.71	1.80	1.89	V

Table 5.1. Recommended Operating Conditions

Note:

1. All minimum and maximum specifications are guaranteed and apply across the recommended operating conditions. Typical values apply at nominal supply voltages and an operating temperature of 25 °C unless otherwise noted.

Table 5.2. DC Characteristics

$(V_{DD} = 1.8 \text{ V} \pm 5\%, V_{DDA} = 3.3 \text{ V} \pm 5$	%, V _{DDO} = 1.8 V ±5%, 2.	5 V ±5%, or 3.3 V ±5%, ٦	Γ _A = -40 to 8	35 °C)		
Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Core Supply Current	I _{DD}	Notes 1, 2	_	175	—	mA
	I _{DDA}		—	120		mA
Output Buffer Supply Current	IDDO	LVPECL Output ³	_	21	25	mA
		@ 156.25 MHz				
		LVDS Output ³	_	15	18	mA
		@ 156.25 MHz				
		3.3 V LVCMOS ⁴	_	21	25	mA
		Output				
		@ 156.25 MHz				
		2.5 V LVCMOS ⁴	_	16	18	mA
		Output				
		@ 156.25 MHz				
		1.8 V LVCMOS ⁴	_	12	13	mA
		Output				
		@ 156.25 MHz				
Total Power Dissipation	P _d	Note 1,5	-	1125	_	mW

$(V_{DD} = 1.8 \text{ V} \pm 5\%, V_{DDA} = 3.3 \text{ V} \pm 5\%, V_{DDO} = 1.8 \text{ V} \pm 5\%, 2.5 \text{ V} \pm 5\%, \text{ or } 3.3 \text{ V} \pm 5\%, T_A = -40 \text{ to } 85 ^{\circ}\text{C})$									
Parameter	Symbol	Test Condition	Min	Тур	Мах	Unit			
Note:									
1. Si5386 test configuration: 8 clock outputs enabled (2 x 983.04 MHz, 2 x 491.52 MHz, 1 x 245.76 MHz, 3 x 122.88 MHz; 2.5 LVDS). Excludes power in termination resistors.									
2. VDDO0 supplies power to both C			olies power t	o both OUT	9 and OUT9	A buffers.			
3. Differential outputs terminated in	•			ita wara aati					
4. LVCMOS outputs measured into = 3, which is the strongest driver		e with 5 pr load. The LV		its were set		105_DRV			
5. Detailed power consumption for a not available. All EVBs support d	, ,	0		hen an evalu	uation board	(EVB) is			
Differential Output Test	Configuration	LVC	MOS Outpu	t Test Con	figuration				
	D- 100 100 D- 0.1 uF			- <u></u> 499 Ω 	56 Ω - 0.1 uF	Ω Scope Input) Ω Scope Input)			

Table 5.3. Input Clock Specifications

(V _{DD} = 1.8 V ±5%, V _{DDA} = 3.3 V ±5%, T _A = -40 to 85 °C)									
Parameter	Symbol	Test Condition	Min	Тур	Мах	Unit			
Standard Differential or Single-Ended/LVCMOS — AC-coupled (IN0, IN1, IN2, IN3)									
Input Frequency Range	f _{IN_DIFF}	Differential	7.68	_	750	MHz			
	f _{IN_SE}	Single-ended/ LVCMOS	7.68	_	250				
Input Voltage Amplitude	V _{IN_DIFF}	f _{IN_DIFF} < 250 MHz	100	—	1800	mVpp_se			
		250 MHz < f _{IN_DIFF} < 750 MHz	225	_	1800	mVpp_se			
Single-Ended Input Amplitude	V _{IN_SE}	f _{IN_SE} < 250 MHz	100	—	3600	mVpp_se			
Slew Rate ^{1, 2}	SR		400	—	_	V/µs			
Duty Cycle	DC		40	_	60	%			
Capacitance	C _{IN}		_	2	_	pF			
Pulsed CMOS — DC-coupled (INC), IN1, IN2, IN3) ³	-	1		1				
Input Frequency	f _{IN_CMOS}		7.68	_	250	MHz			
Input Voltage	V _{IL}		-0.2	_	0.33	V			
	V _{IH}		0.49	_	_	V			
Slew Rate ^{1, 2}	SR		400	_	—	V/µs			
Duty Cycle	DC	Clock Input	40	_	60	%			

(V _{DD} = 1.8 V ±5%, V _{DDA} = 3.3 V ±5%, T _A = -40 to 85 °C)									
Parameter	Symbol	Test Condition	Min	Тур	Max	Unit			
Minimum Pulse Width	PW	Pulse Input	1.6	—	_	ns			
Input Resistance	R _{IN}		—	8	_	kΩ			
XO (applied to XA/XB) ⁴									
Frequency	f _{IN_REF}		_	54	_	MHz			
Total Frequency Tolerance ⁵	fRANGE		-50	_	+50	ppm			
Input Voltage Amplitude	V _{IN_SE}	Single-ended Input	365	_	2000	mVpp_se			
	V _{IN_DIFF}	Differential Input	365	_	2500	mVpp_diff			
Slew Rate ^{1, 2}	SR	Single-ended Input	1500	_	_	V/µs			
	SR _{IN_DIFF}	Differential Input	400	_	_	V/µs			
Input Duty Cycle	DC		40	_	60	%			
Activity Dip ⁶					2	ppm/C			

1. Imposed for phase noise performance.

- 2. Rise and fall times can be estimated using the following simplified equation: tr/tf80-20 = ((0.8 0.2) * VIN_Vpp_se) / SR.
- 3. Pulsed CMOS mode is intended primarily for single-ended LVCMOS input clocks <1 MHz, which must be dc-coupled, having a duty cycle significantly less than 50%. A typical application example is a low frequency video frame sync pulse. Since the input thresholds (VIL, VIH) of this buffer are non-standard, refer to the input attenuator circuit for dc-coupled Pulsed LVCMOS in the Si5386 Reference Manual. Otherwise, for standard LVCMOS input clocks, use the "AC-coupled Singled-Ended" mode as shown in 3.6.6 Input Configuration and Terminations.
- 4. Refer to the Si534x/8x Jitter Attenuators Recommended Crystal, TCXO and OCXOs Reference Manual for recommended 54 MHz XOs.

5. Includes aging and temperature affects.

6. Activity dip is also called frequency perturbation.

Table 5.4. Serial and Control Input Pin Specifications

(V _{DD} = 1.8 V ±5%, V _{DDA} = 3.3 V ±5%, V _{DDS} = 3.3 V ±5%, 1.8 V ±5%, T _A = –40 to 85 °C)										
Parameter	Symbol	Test Condition	Min	Тур	Мах	Unit				
Serial and Control Input Pins (IN_SEL[1:0], RSTb, OEb, PDNb, A1/SDO, SCLK, A0/CSb, SDA/SDIO)										
Input Voltage Thresholds	VIL		_		0.3 x V _{DDIO} ¹	V				
	V _{IH}		0.7 x V _{DDIO} ¹	_		V				
Input Capacitance	C _{IN}		_	2	_	pF				
Input Resistance	١L		_	20	_	kΩ				
Minimum Pulse Width	PW	RSTb, PDNb	100	_	_	ns				

Note:

1. V_{DDIO} is determined by the IO_VDD_SEL bit. It is selectable as V_{DDA} or V_{DD}. See the Si5386 Reference Manual for more details on the register settings.

(V _{DD} = 1.8 V ±5%, V _{DDA} = 3.3 V							
Parameter	Symbol	Test Co	ondition	Min	Тур	Max	Unit
Output Frequency ⁶	fout	N >= 10		0.0001	_	1474.56	MHz
		N :	= 9		1638.4		MHz
		N = 8			1843.2		MHz
		N = 7 ⁷		_	2106.53		MHz
		N = 6			2457.6		MHz
		N :	= 5		2949.12		MHz
Duty Cycle	DC	fOUT < 4	400 MHz	48	_	52	%
		400 MHz < f _O	_{UT} < 800 MHz	45	_	55	%
		800 MHz < fOUT	800 MHz < fOUT < 1474.56 MHz		_	60	%
		f > 1474	.56 MHz	25	_	75	%
Output-Output Skew ⁷	Т _{SK}	Differential output			0	75	ps
		Specified for outputs using the same MultiSynth					
			Specified for outputs nt MultiSynths	-150	0	150	ps
OUT-OUTb Skew	Т _{SK_OUT}	Measured from the positive to negative output pins		-	0	50	ps
Output Voltage Amplitude ¹			Normal Mode)	1		
	V _{OUT}	V _{DDO} = 3.3 V, 2.5 V, or 1.8 V	LVDS	350	470	550	mVpp_se
		V _{DDO} = 3.3 V, 2.5 V	LVPECL	660	810	1000	
Common Mode Voltage ^{1,2, 3}		le					
-	VCM	V _{DDO} = 3.3 V	LVDS	1.10	1.25	1.35	V
			LVPECL	1.90	2.05	2.15	
		V _{DDO} = 2.5 V	LVPECL, LVDS	1.15	1.25	1.35	
		V _{DDO} = 1.8 V	sub-LVDS	0.87	0.93	1.00	
Rise and Fall Times (20% to 80%)	t _R /t _F	Norma	l Mode	_	170	240	ps
Differential Output Impe- dance ²	Z _O	Norma	I Mode	_	100		Ω
Power Supply Noise Rejec-	PSRR		Norm	al Mode		<u> </u>	
tion ⁴		10 kHz sinu	soidal noise	_	-93		dBc
		100 kHz sinu	usoidal noise	_	-93		
				_	-84		
		500 kHz sinusoidal noise			-79		

Table 5.5. Differential Clock Output Specifications

$(V_{DD} = 1.8 \text{ V} \pm 5\%, V_{DDA} = 3.3 \text{ V} \pm 5\%, V_{DDO} = 1.8 \text{ V} \pm 5\%, 2.5 \text{ V} \pm 5\%, \text{ or } 3.3 \text{ V} \pm 5\%, T_A = -40 \text{ to } 85 \text{ °C})$								
Symbol	Test Condition	Min	Тур	Max	Unit			
XTALK	Differential	_	-75	_	dB			
	Symbol	Symbol Test Condition	Symbol Test Condition Min	Symbol Test Condition Min Typ	Symbol Test Condition Min Typ Max			

- 1. Output amplitude and common mode voltage are programmable through register settings and can be stored in NVM. Each output driver can be programmed independently. The typical normal mode (or low power mode) LVDS maximum is 100 mV (or 80 mV) higher than the TIA/EIA-644 maximum. Refer to the Si5386 Reference Manual for recommended output settings.
- 2. Not all combinations of voltage amplitude and common mode voltages settings are possible.
- 3. Driver output impedance depends on selected output mode (Normal, Low Power). Refer to the Si5386 Reference Manual for more information.
- 4. Measured for 156.25 MHz carrier frequency. Sinewave noise added to VDDO (1.8 V = 50 mVpp, 2.5 V/3.3 V = 100 mVpp) and noise spur amplitude measured.
- 5. Measured across two adjacent outputs, both in LVDS mode, with the victim running at 122.88 MHz and the aggressor at 156.25 MHz. Refer to application note, "AN862: Optimizing Si534x Jitter Performance in Next Generation Internet Infrastructure Systems", guidance on crosstalk minimization. Note that all active outputs must be terminated when measuring crosstalk.
- 6. VDDO = 2.5 V or 3.3 V required for fOUT > 1474.56 MHz
- 7. For any R divider settings that differ by a power of 2.



Table 5.6. LVCMOS Clock Output Specifications

(V _{DD} = 1.8 V ±5%, V _{DDA} = 3.3 V ±5%, V _{DDO} = 1.8 V ±5%, 2.5 V ±5%, or 3.3 V ±5%, T _A = –40 to 85 °C)										
Parameter	Symbol	Test Co	ndition	Min	Тур	Max	Unit			
Output Frequency	fout			0.0001	_	250	MHz			
Duty Cycle	DC	fOUT <100 MHz		47	_	53	%			
		100 MHz < fOL	44	_	55					
Output Voltage High ^{1, 2, 3}	V _{OH}	VDDO = 3.3 V								
		OUTx_CMOS_DRV=1	IOH = -10 mA	VDDO x	_	_	V			
		OUTx_CMOS_DRV=2	IOH = -12 mA	0.75	_	_				
		OUTx_CMOS_DRV=3	IOH = -17 mA		_	-				
		VDDO = 2.5 V								
		OUTx_CMOS_DRV=1	IOH =6 mA	VDDO x	_	_	V			
		OUTx_CMOS_DRV=2	IOH =8 mA	0.75	_	_				
		OUTx_CMOS_DRV=3	IOH = -11 mA		_	_				
		VDDO = 1.8 V								
		OUTx_CMOS_DRV=2	IOH =4 mA	VDDO x	_	_	V			
		OUTx_CMOS_DRV=3	IOH = -5 mA	0.75	—	_				

(V _{DD} = 1.8 V ±5%, V _{DDA} = 3.3	$(V_{DD}$ = 1.8 V ±5%, V_{DDA} = 3.3 V ±5%, V_{DDO} = 1.8 V ±5%, 2.5 V ±5%, or 3.3 V ±5%, T_A = -40 to 85 °C)									
Parameter	Symbol	Test Co	Test Condition			Max	Unit			
Output Voltage Low ^{1, 2, 3}	V _{OL}	VDDO = 3.3 V								
		OUTx_CMOS_DRV=1	IOL = 10 mA	_	_	VDDO x	V			
		OUTx_CMOS_DRV=2	IOL = 12 mA	—	_	- 0.15				
		OUTx_CMOS_DRV=3	IOL = 17 mA	_	_					
		VDDO = 2.5 V								
		OUTx_CMOS_DRV=1	IOL = 6 mA	_	_	VDDO x 0.15	V			
		OUTx_CMOS_DRV=2	IOL = 8 mA	_	_					
		OUTx_CMOS_DRV=3	IOL = 11 mA	_	_					
		VDDO = 1.8 V								
		OUTx_CMOS_DRV=2	IOL = 4 mA	_	_	VDDO x	V			
		OUTx_CMOS_DRV=3	IOL = 5 mA	_	_	0.15				
LVCMOS Rise and Fall	tr/tf	VDDO =	= 3.3 V	_	420	550	ps			
Times ³		VDDO = 2.5 V		_	475	625	ps			
(20% to 80%)		VDDO = 1.8 V		-	525	705	ps			

1. Driver strength is a register programmable setting and stored in NVM. Options are OUTx_CMOS_DRV = 1, 2, 3. Refer to the Si5386 Reference Manual for more details on register settings.

2. IOL/IOH is measured at VOL/VOH as shown in the dc test configuration.

3. A 5 pF capacitive load is assumed. The LVCMOS outputs were set to OUTx_CMOS_DRV = 3.

DC Test Configuration

AC Output Test Configuration

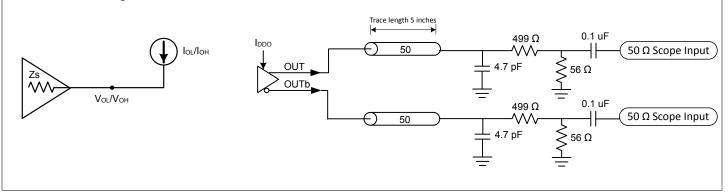


Table 5.7. Output Serial and Status Pin Specifications

$(V_{DD} = 1.8 \text{ V} \pm 5\%, V_{DDA} = 3.3 \text{ V} \pm 5\%, V_{DDS} = 3.3 \text{ V} \pm 5\%, 1.8 \text{ V} \pm 5\%, T_A = -40 \text{ to } 85 \text{ °C})$										
Parameter	Symbol	Test Condition	Min	Min Typ Max U						
Serial and Status Output Pins (INTRb, LOLb, SDA/SDIO ² , A1/SDO)										
Output Voltage	V _{OH}	IOH = –2 mA	V _{DDIO} ¹ x 0.75	_		V				
	V _{OL}	IOL = 2 mA			V _{DDIO} 1 x 0.15	V				

(V _{DD} = 1.8 V ±5%, V _{DDA} = 3.3 V ±5%, V _{DDS} = 3.3 V ±5%, 1.8 V ±5%, T _A = –40 to 85 °C)									
Parameter	Symbol	Test Condition	Min	Тур	Max	Unit			
Note: 1. V _{DDIO} is determined by th				•		Clock-			
Builder Pro GUI. Alternative 2. The V _{OH} specification doe with I2C SEL pulled high	es not apply to the op	en-drain SDA/SDIO c		•	•	unused			

Table 5.8. Performance Characteristics	Table 5.8.	Performance	Characteristics
--	------------	-------------	-----------------

(V _{DD} = 1.8 V ±5%, or 3.3 V ±5%, V _{DDA}	Δ = 3.3 V ±5%, T _A = ·	–40 to 85 °C)				
Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
PLL Loop Bandwidth	f _{BW}		1	-	4000	Hz
Programming Range ¹						
Initial Start-Up Time	tstart	Time from power-up or de-as- sertion of PDNb to when the device generates free-running clocks	_	30	45	ms
PLL Lock Time	tacq	Fastlock enabled, fIN = 19.44 MHz ²	—	500	600	ms
		11N = 19.44 MHZ ²				
POR to Serial Interface Ready ³	t _{RDY}		_	15	—	ms
Input-to-Output Delay Variation	t _{IODELAY}	Different parts and outputs	—	-	1.2	ns
Jitter Peaking	J _{PK}	25 MHz input, 25 MHz output, loop bandwidth of 4 Hz	—	_	0.1	dB
Jitter Tolerance	J _{TOL}	Compliant with G.8262 Op- tions 1&2 Carrier Frequency = 10.3125 GHz	_	3180	_	UI pk-pk
		Jitter Modulation Frequency = 10 Hz				
Maximum Phase Transient	tswitch	Single automatic switch be- tween two 2 MHz inputs, DSPLL BW = 400 Hz	—	0.2	0.3	ns
		Single manual switch between two 2 MHz inputs, DSPLL BW = 400 Hz	—	0.2	0.25	ns
Pull-in Range	ωΡ		_	20	_	ppm
RMS Jitter Generation ⁴	J _{GEN}	12 kHz to 20 MHz		72	_	fs RMS

(V _{DD} = 1.8 V ±5%, or 3.3 V ±5%, V _{DDA} = 3.3 V ±5%, T _A = –40 to 85 °C)									
Parameter	Symbol	Test Condition	Min	Тур	Max	Unit			
Phase Noise Performance ⁴ (122.88	PN	100 Hz	—	-118	_	dBc/Hz			
MHz Carrier Frequency)		1 kHz		-133	_	dBc/Hz			
		10 kHz		-142	_	dBc/Hz			
		100 kHz	—	-149	_	dBc/Hz			
		1 MHz	—	-154	_	dBc/Hz			
		10 MHz	—	-165	_	dBc/Hz			
MultiSynth Spur Performance	SPUR	From 1 MHz to 30 MHz offset	—	-95	_	dBc			

1. Actual loop bandwidth may be lower; please refer to CBPro for actual value on your frequency plan.

2. Lock Time can vary significantly depending on several parameters, such as bandwidths, LOL thresholds, etc. For this case, lock time was measured with nominal and fastlock bandwidths, both set to 100 Hz, LOL set/clear thresholds of 3/0.3 ppm respectively, using IN0 as clock reference by removing the reference and enabling it again, then measuring the delta time between the first rising edge of the clock reference and the LOL indicator de-assertion.

3. Measured as time from valid VDD/VDDA rails (90% of their value) to when the serial interface is ready to respond to commands.

4. Jitter generation test conditions: fIN=156.25MHz, DSPLL LBW = 40Hz. Jitter integrated from 12 kHz to 20 MHz offset. Does not include jitter from PLL input reference.

Parameter	Symbol	Test Condition	Min	Max	Min	Max	Unit
			Standard M	ode	Fast Mode		
			100 kbps		400 kbps		
SCL Clock Frequency	f _{SCL}		_	100	_	400	kHz
SMBus Timeout	_	When Timeout is Enabled	25	35	25	35	ms
Hold Time (Repeated) START Condition	t _{HD:STA}		4.0	_	0.6	_	μs
Low Period of the SCL Clock	t _{LOW}		4.7	_	1.3	_	μs
HIGH Period of the SCL Clock	thigh		4.0	_	0.6	_	μs
Set-up Time for a Repea- ted START Condition	t _{SU:STA}		4.7	_	0.6	_	μs
Data Hold Time	t _{HD:DAT}		100	_	100	_	ns
Data Set-up Time	t _{SU:DAT}		250	_	100	_	ns
Rise Time of Both SDA and SCL Signals	tr		_	1000	20	300	ns
Fall Time of Both SDA and SCL Signals	t _f		_	300	—	300	ns
Set-up Time for STOP Condition	t _{SU:STO}		4.0	_	0.6	_	μs

Table 5.9. I2C Timing Specifications (SCL,SDA)

Parameter	Symbol	Test Condition	Min	Max	Min	Max	Unit
Bus Free Time between a STOP and START Condi- tion	t _{BUF}		4.7	—	1.3	_	μs
Data Valid Time	t _{VD:DAT}		_	3.45	_	0.9	μs
Data Valid Acknowledge Time	t _{VD:ACK}		_	3.45	—	0.9	μs

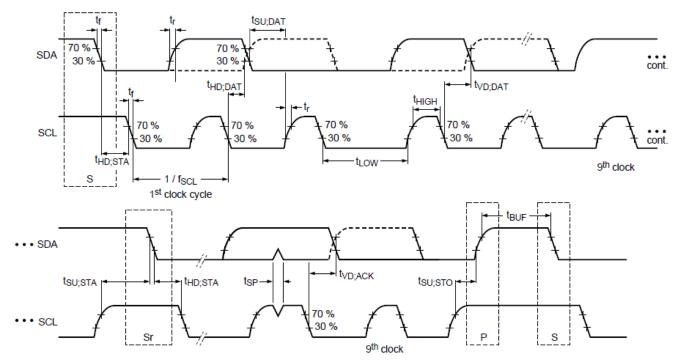


Figure 5.1. I²C Serial Port Timing Standard and Fast Modes

Parameter	Symbol	Min	Тур	Max	Unit
SCLK Frequency	f _{SPI}	_	_	20	MHz
SCLK Duty Cycle	T _{DC}	40	_	60	%
SCLK Period	T _C	50	_	_	ns
Delay Time, SCLK Fall to SDO Active	T _{D1}	_	_	18	ns
Delay Time, SCLK Fall to SDO	T _{D2}	_	_	15	ns
Delay Time, CSb Rise to SDO Tri-State	T _{D3}	_	_	15	ns
Setup Time, CSb to SCLK	T _{SU1}	5	_	_	ns
Hold Time, SCLK Fall to CSb	T _{H1}	5	_	_	ns
Setup Time, SDI to SCLK Rise	T _{SU2}	5	_	_	ns
Hold Time, SDI to SCLK Rise	T _{H2}	5	_	_	ns

Table 5.10. SPI Timing Specifications (4-Wire)

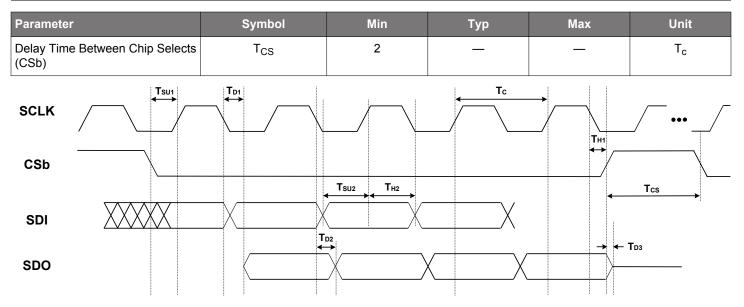
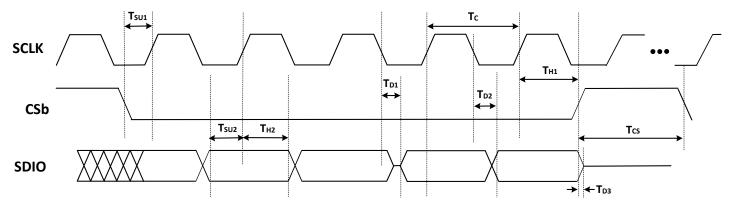


Figure 5.2. 4-Wire SPI Serial Interface Timing

Table 5.11. SPI Timing Specifications (3-Wire)

Parameter	Symbol	Min	Тур	Max	Unit
SCLK Frequency	f _{SPI}	_	_	20	MHz
SCLK Duty Cycle	T _{DC}	40	_	60	%
SCLK Period	T _C	50			ns
Delay Time, SCLK Fall to SDIO Turn-on	T _{D1}			20	ns
Delay Time, SCLK Fall to SDIO Next-bit	T _{D2}	_	_	15	ns
Delay Time, CSb Rise to SDIO Tri-State	T _{D3}			15	ns
Setup Time, CSb to SCLK	T _{SU1}	5			ns
Hold Time, SCLK Fall to CSb	T _{H1}	5	_	_	ns
Setup Time, SDI to SCLK Rise	T _{SU2}	5		_	ns
Hold Time, SDI to SCLK Rise	T _{H2}	5	_	_	ns
Delay Time Between Chip Selects (CSb)	T _{CS}	2	_		T _c





Parameter	Symbol	Test Condition1	Value	Unit
Thermal Resistance	θ _{JA}	Still Air	22	°C/W
Junction to Ambient		Air Flow 1 m/s	19.4	
		Air Flow 2 m/s	18.3	
Thermal Resistance	θ _{JC}		9.5	
Junction to Case				
Thermal Resistance	θ _{JB}		9.4	
Junction to Board	Ψ _{JB}		9.3	
Thermal Resistance	Ψ_{JT}		0.2	-
Junction to Top Center				
Note: 1. Based on PCB Dimension: 3" x 4.5", PCB	Thickness: 1.6 mm, PCE	3 Land/Via under GNP pad: 36,	Number of Cu L	ayers: 4

Table 5.12. Thermal Characteristics (QFN-64)

Table 5.13. Absolute Maximum^{1, 2, 3}

Parameter	Symbol	Test Condition	Value	Unit	
DC Supply Voltage	VDD		-0.5 to 3.8	V	
	VDDA		-0.5 to 3.8	V	
	VDDO		-0.5 to 3.8	V	
Input Voltage Range	VI1	INO – IN3	-0.85 to 3.8	V	
	VI2	IN_SEL[1:0], RSTb, PDNb, OEb, I2C_SEL, SYNC	-0.5 to 3.8	V	
		SDA/SDIO, A1/SDO, SCLK, A0/CSb			
	VI3	XA/XB	-0.5 to 2.7	V	
Latch-up Tolerance	LU		JESD78 Compliant		
ESD Tolerance	HBM	100 pF, 1.5 kΩ	2.0	kV	
Junction Temperature	T _{JCT}		-55 to 125	°C	
Storage Temperature Range	T _{STG}		–55 to +150	°C	
Soldering Temperature	T _{PEAK}		260	°C	
(Pb-free profile) ²					
Soldering Temperature Time at TPEAK(Pb-free profile) ³	T _P		20–40	sec	

Si5386 Data Shee	et
Electrical Specification	s

Parameter	Symbol	Test Condition	Value	Unit
Note:				
 Permanent device damage may occur if the conditions as specified in the operati tended periods may affect device reliabil 	onal sections of this da			
2. For detailed MSL and packaging informa	ation, go to RoHS Infor	mation.		
3. The device is compliant with JEDEC J-S	TD-020.			

6. Typical Application Schematic

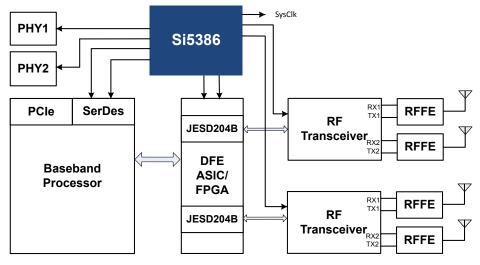


Figure 6.1. Application Block Diagram of µBTS

7. Detailed Block Diagrams

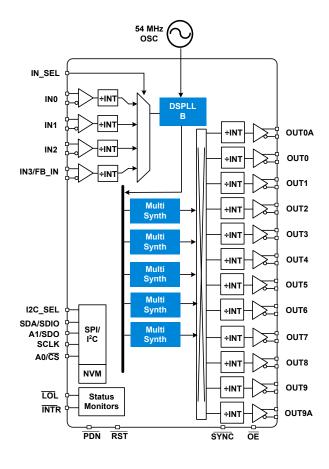


Figure 7.1. Si5386 Block Diagram

8. Typical Operating Characteristics

The phase noise plots below were taken under the following conditions: V_{DD} = 1.8 V; V_{DDA} = 3.3 V; V_{DDS} = 3.3 V, 1.8 V; OLBW = 40Hz; T_a = 25 °C.

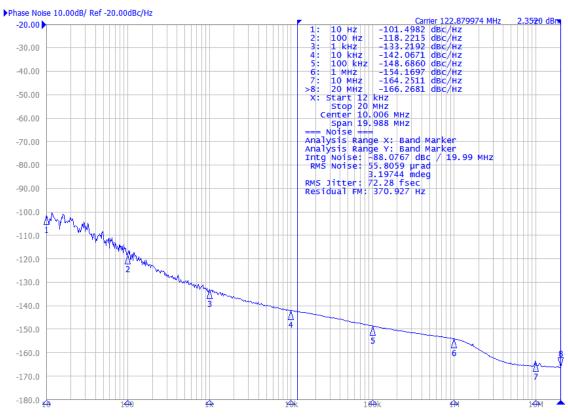
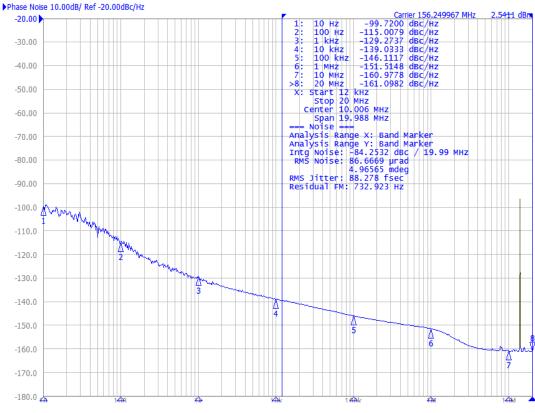


Figure 8.1. f_{IN} = 156.25 MHz, f_{OUT} = 122.88 MHz





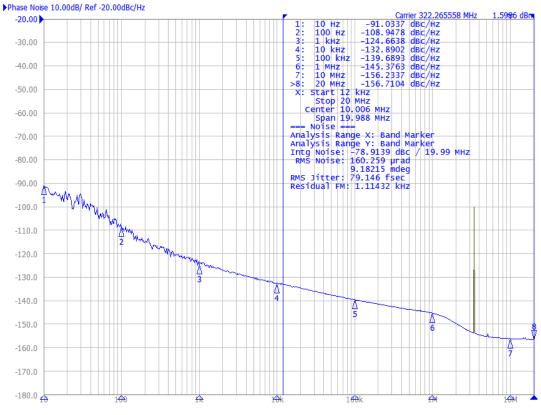


Figure 8.3. f_{IN} = 322.265625 MHz, f_{OUT} = 322.265625 MHz

9. Pin Descriptions

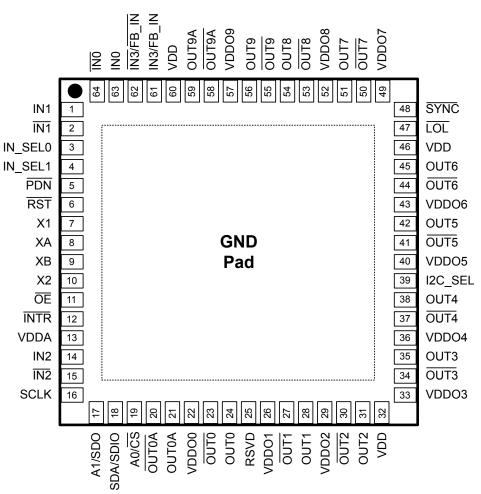


Table 9.1.	Si5386	Pin	Descriptions
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Pin	Pin Number	Pin	Function
Name		Type ¹	
Inputs			
IN0	63	I	Clock Inputs. These pins accept
IN0b	64	I	an input clock for synchronizing the device. They support both
IN1	1	I	differential and single-ended clock signals. Refer to section
IN1b	2	I	3.6 Inputs (IN0, IN1, IN2, IN3) for input termination options.
IN2	14	I	These pins are high-impedance
IN2b	15	I	and must be terminated exter- nally, when being used. The negative side of the differential input must be ac-grounded when accepting a single-ended clock. Unused inputs may be left unconnected.
IN3/FB_IN	61	I	Clock Input 3/External Feed-
IN3/FB_INb	62		 back Input. By default, these pins are used as the 4th clock input (IN3/IN3). They can also be used as the external feedback input (FB_IN/ FB_IN) for the optional zero de- lay mode. See section 3.6.1 Manual Input Switching (IN0, IN1, IN2, IN3) for details on the optional zero delay mode.
Outputs			

Pin	Pin Number	Pin	Function
Name		Type ¹	
OUT0A	21	0	Output Clocks. These output
OUT0Ab	20	0	clocks support a programmable signal swing and common mode
OUT0	24	0	voltage. Desired output signal format is configurable using reg-
OUT0b	23	0	ister control. Termination rec-
OUT1	28	0	ommendations are provided in section 3.8.3 Output Termina-
OUT1b	27	0	tions and section LVCMOS Out- put Impedance and Drive
OUT2	31	0	Strength Selection. Unused out- puts should be left unconnec-
OUT2b	30	0	ted.
OUT3	35	0	
OUT3b	34	0	
OUT4	38	0	
OUT4b	37	0	
OUT5	42	0	
OUT5b	41	0	
OUT6	45	0	
OUT6b	44	0	
OUT7	51	0	
OUT7b	50	0	
OUT8	54	0	
OUT8b	53	0	
OUT9	56	0	
OUT9b	55	0	
OUT9A	59	0	
OUT9Ab	58	0	
Serial Interface	·		
I2C_SEL	39	1	I2C Select. This pin selects the serial interface mode as I2C (I2C_SEL = 1) or SPI (I2C_SEL = 0). This pin is internally pulled high.
SDA/SDIO	18	I/O	Serial Data Interface. This is the bidirectional data pin (SDA) for the I2C mode, the bidirec- tional data pin (SDIO) in the 3- wire SPI mode, or the input data pin (SDI) in 4-wire SPI mode. When in I2C mode, this pin must be pulled-up using an external resistor of at least 1 kW. No pull-up resistor is needed when in SPI mode. This pin is 3.3 V tolerant.

Pin Name	Pin Number	Pin Type ¹	Function
A1/SDO	17	I/O	Address Select 1/Serial Data Output. In I2C mode this pin functions as the A1 address input pin. In 4-wire SPI mode, this is the serial data output (SDO) pin. This pin is 3.3 V tolerant.
SCLK	16		Serial Clock Input. This pin functions as the serial clock in- put for both I2C and SPI modes. When in I2C mode, this pin must be pulled-up us- ing an external resistor of at least 1 kW. No pull-up resistor is needed when in SPI mode. This pin is 3.3 V tolerant.
A0/CSb	19	Ι	Address Select 0/Chip Select. This pin functions as the hard- ware controlled address A0 in I2C mode. In SPI mode, this pin functions as the chip select in- put (active low). This pin is inter- nally pulled-up. This pin is 3.3 V tolerant.
Control/Status			
INTRb	12	0	Interrupt ² . This pin is asserted low when a change in device status has occurred. This pin must be pulled-up using an ex- ternal resistor of at least 1 kW. It should be left unconnected when not in use.
PDNb	5	Ι	Power Down ² . The device enters into a low power mode when this pin is pulled low. This pin is internally pulled-up. This pin is 3.3 V tolerant. It can be left unconnected when not in use.
RSTb	6	Ι	Device Reset. ² Active low input that performs power-on reset (POR) of the device. Resets all internal logic to a known state and forces the device registers to their default values. Clock outputs are disabled during reset. This pin is internally pulled-up. This pin is 3.3 V tolerant.
OEb	11	Ι	Output Enable ² . This pin disables all outputs when held high. This pin is internally pulled low and can be left unconnected when not in use. This pin is 3.3 V tolerant.

Pin	Pin Number	Pin	Function
Name		Type ¹	
LOLb	47	0	Loss Of Lock ² . This output pin indicates when the DSPLL is locked (high) or out-of-lock (low). It can be left unconnected when not in use.
SYNC	48	I	Output Clock Synchroniza- tion ² . An active low signal on this pin resets the output divid- ers for the purpose of re-align- ing the output clocks. This pin is internally pulled-up and can be left unconnected when not in use.
IN_SEL0	3	I	Input Reference Select ² . The
IN_SEL1	4	I	IN_SEL[1:0] pins are used in manual pin controlled mode to select the active clock input as shown in Table 3.1 Manual In- put Selection Using IN_SEL[1:0] Pins on page 9
ХА	8	I	Oscillator input. Single-ended
ХВ	9	I	input must be connected to the XA pin, with the XB pin appro- priately terminated.
RSVD	7	NC	Reserved. Leave disconnected.
	10	NC	
	25	NC	
Power			
VDD	32	Р	Core Supply Voltage. The de-
VDD	46	Р	vice operates from a 1.8 V sup- ply. A 1 uF bypass capacitor
VDD	60	Р	should be placed very close to each pin.
VDDA	13	P	Core Supply Voltage 3.3 V. This core supply pin requires a 3.3 V power source. A 1 uF bypass capacitor should be placed very close to this pin.

Pin	Pin Number	Pin	Function
Name		Type ¹	
VDDO0	22	Р	Output Clock Supply Voltage.
VDDO1	26	Р	Supply voltage (3.3 V, 2.5 V, 1.8 V) for OUTn, OUTn outputs.
VDDO2	29	Р	Note that VDDO0 supplies pow- er to OUT0 and OUT0A;
VDDO3	33	Р	VDDO9 supplies power to
VDDO4	36	Р	OUT9 and OUT9A. Leave VDDO pins of unused output
VDDO5	40	Р	drivers unconnected. An alter- native option is to connect the
VDDO6	43	Р	VDDO pin to a power supply and disable the output driver to
VDD07	49	Р	minimize current consumption.
VDDO8	52	Р	
VDDO9	57	Р	
GND PAD		Р	Ground Pad. This pad provides connection to ground and must be connected for proper opera- tion.

1. I = Input, O = Output, P = Power

2. The IO_VDD_SEL control bit (0x0943 bit 0) selects 3.3 V or 1.8 V operation.

10. Package Outlines

10.1 Si5386 9x9 mm 64-QFN Package Diagram

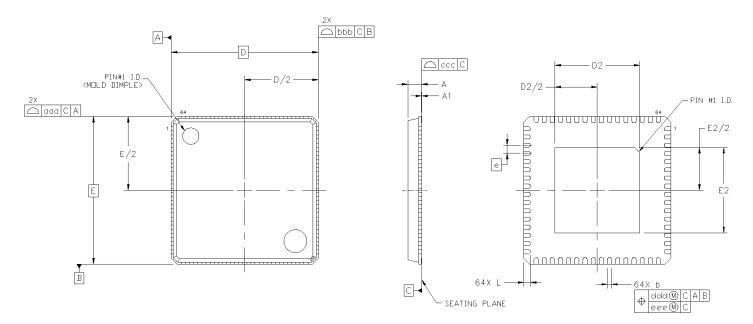


Figure 10.1. Si5386 9x9 mm 64-QFN Package Diagram

Dimension	MIN	NOM	МАХ
A	0.80	0.85	0.90
A1	0.00	0.02	0.05
b	0.18	0.25	0.30
D		9.00 BSC	
D2	5.10	5.20	5.30
e	0.50 BSC		
E	9.00 BSC		
E2	5.10	5.20	5.30
L	0.30	0.40	0.50
ааа	—	—	0.15
bbb	—	_	0.10
CCC	—	—	0.08
ddd	—	_	0.10

Table 10.1. Package Diagram Dimensions

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.

2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

3. This drawing conforms to the JEDEC Solid State Outline MO-220.

4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

11. PCB Land Pattern

The following figure illustrates the PCB land pattern details for the devices. The table lists the values for the dimensions shown in the illustration.

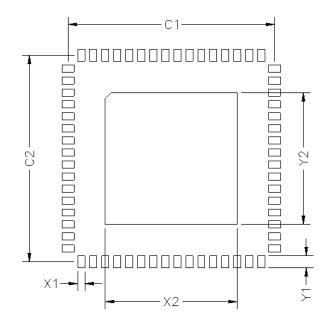


Figure 11.1. PCB Land Pattern

Table 11.1. PCB Land Pattern Dimensions

Dimension	Si5386 (Max)
C1	8.6
C2	8.6
E	0.50
X1	0.30
Y1	0.50
X2	5.5
Y2	5.5

Notes:

General

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. This Land Pattern Design is based on the IPC-7351 guidelines.
- 3. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition is calculated based on a fabrication Allowance of 0.05 mm.

Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

Stencil Design

- 1. A stainless steel, laser-cut and electropolished stencil with trapezoidal walls should be used to assure good solder paste release.
- 2. The stencil thickness should be 0.125 mm (5 mils).
- 3. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
- 4. A 2x2 array of 0.65mm square openings on a 0.90mm pitch should be used for the center ground pad.

Card Assembly

- 1. A No-Clean, Type-3 solder paste is recommended.
- 2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

12. Top Marking

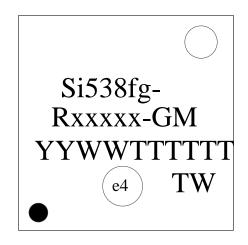




Table 12.1. Top Marking Explanation

Line	Characters	Description
		Base part number and Device Grade for Any-frequency, Any-output, Jitter Cleaning Clock (single PLL):
1	Si538fg-	f = 6, 12-Output LTE + Ethernet Clock
		g = Grade (internal versus external crystal oscillator option)
		R = Product revision. (Refer to 2. Ordering Guide for latest revision).
2	2 Rxxxx-GM	xxxxx = Customer specific NVM sequence number. Optional NVM code as- signed for custom, factory pre-programmed devices.
2		Characters are not included for standard, factory default configured devices. See 2. Ordering Guide for more information.
		-GM = Package (LGA) and temperature range (–40 to +85 °C)
3	YYWWTTTTTT	YYWW = Characters correspond to the year (YY) and work week (WW) of package assembly.
		TTTTTT = Manufacturing trace code.
	Circle w/ 1.6 mm (64-QFN) diameter	Pin 1 indicator; left-justified
4	e4	Pb-free symbol; Center-Justified
	TW	TW = Taiwan; Country of Origin (ISO Abbreviation)

13. Device Errata

Log in or register at https://www.silabs.com/support/resources.ct-errata.p-timing_clocks to access the device errata document.

14. Document Change List

14.1 Revision 1.01

April, 2019

- Tightened Output-Out Skew (different MultiSynths) specifications.
- Added Input-Output Delay Variation specifications.

14.2 Revision 1.0

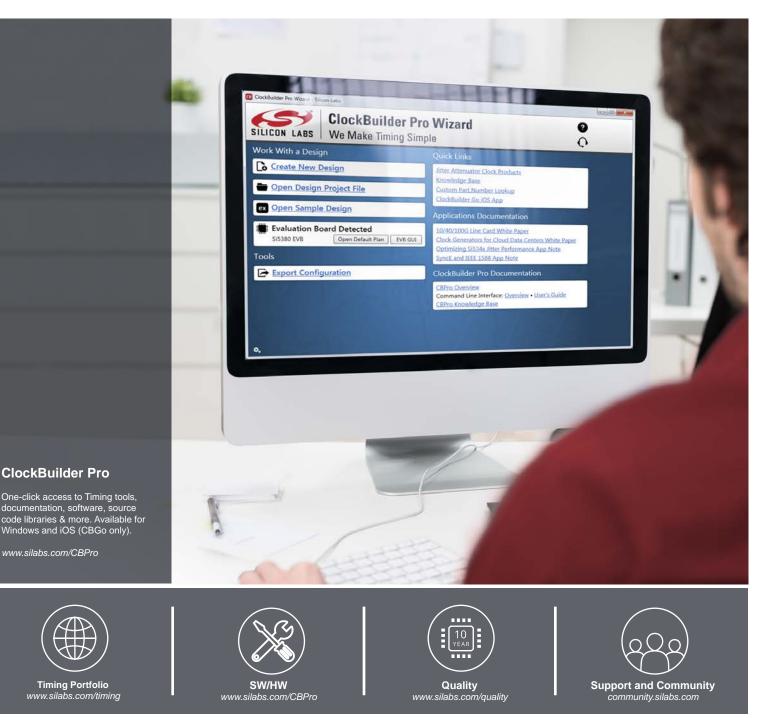
July, 2018

- Final release.
 - Updated tables, block diagrams, and figures throughout the document.
 - Added and removed sections.

14.3 Revision 0.9

September, 2017

Initial release.



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